Se	earch	Notes	3

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/766,675	HUBERT ET AL.	
Examiner	Art Unit	
Maikhanh Nguyen	2176	

SEARCHED			
Class	Subclass	Date	Examiner
715	500 501.1 511 526	8/9/2006	МК
707	10 102	8/9/2006	MK
	203 204	8/9/2006	MK
Updated	above	2/16/2007	MK
Updated	above	7/30/2007	MK
Updated	above	2/7/2008	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH))
	DATE	EXMR
Inventor Name Search	8/9/2006	МК
West Search (USPAT, USGPub, EPO, JPO, DERWENT) See Search Historty Printout	8/9/2006	МК
West Updated (USPAT, USGPub, EPO, JPO,DERWENT) See Search Historty Printout	2/16/2007	МК
West Updated (USPAT, USGPub, EPO, JPO,DERWENT) See Search Historty Printout	7/29/2007	MĶ
NPL(ACM)	7/30/2007	MK
West Updated (USPAT, USPGPub) See Search History Printout	2/7/2008	MK